# MOSFET – Power, Single N-Channel 40 V, 0.42 mΩ, 554.5 A

#### **Features**

- Small Footprint (8x8 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- Wettable Flank Plated for Enhanced Optical Inspection
- AEC-101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	40	٧
Gate-to-Source Voltage	Э		V <sub>GS</sub>	±20	V
Continuous Drain	Steady State	T <sub>C</sub> = 25°C	I <sub>D</sub>	554.5	Α
Current R <sub>θJC</sub> (Note 2)	State	T <sub>C</sub> = 100°C		392.1	
Power Dissipation	Steady	T <sub>C</sub> = 25°C	$P_{D}$	245.4	W
R <sub>θJC</sub> (Note 2)	Note 2) State			122.7	
Continuous Drain	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	78.9	Α
Current R <sub>0JA</sub> (Notes 1, 2)	State	T <sub>A</sub> = 100°C		55.8	
Power Dissipation	Power Dissipation $R_{\theta JA}$ (Notes 1, 2) Steady $T_A = 25^{\circ}C$ $T_A = 100^{\circ}C$		$P_{D}$	5.0	W
H <sub>θ</sub> JA (Notes 1, 2)				2.5	
Pulsed Drain Current	T <sub>A</sub> = 25	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	900	Α
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	204.5	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 52.7 A)			E <sub>AS</sub>	2058	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Note 2)	$R_{\theta JC}$	0.61	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	30.2	

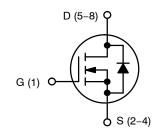
- 1. Surface-mounted on FR4 board using a 1 in<sup>2</sup> pad size, 1 oz. Cu pad.
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.



#### ON Semiconductor®

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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
40 V	0.42 m $\Omega$ @ 10 V	5545 A
	0.66 m $\Omega$ @ 4.5 V	554.5 A



**N-CHANNEL MOSFET** 



#### **MARKING DIAGRAM**



XXX = Device Code (8 A-N characters max)

= Assembly Location

WL = 2-digit Wafer Lot Code

Y = Year Code

WW = Work Week Code

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condi	tion	Min	Тур	Max	Unit	
OFF CHARACTERISTICS	-				<u> </u>		-	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D =$	250 μΑ	40			V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>	I <sub>D</sub> = 250 μA, ref to 25°C			12.6		mV/°C	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V$ ,	T <sub>J</sub> = 25°C			10	_	
		$V_{DS} = 40 \text{ V}$	T <sub>J</sub> = 125°C			250	μΑ	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub>	; = 20 V			100	nA	
ON CHARACTERISTICS (Note 3)					•		•	
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D =$	= 250 μA	1.2		2.0	V	
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>	I <sub>D</sub> = 250 μA, re	f to 25°C		-6.0		mV/°C	
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 50 A		0.35	0.42		
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 50 A		0.52	0.66	mΩ	
Forward Transconductance	9FS	V <sub>DS</sub> =5 V, I <sub>D</sub> = 50 A			323		S	
Gate Resistance	$R_{G}$	T <sub>A</sub> = 25°C			1.0		Ω	
CHARGES, CAPACITANCES & GATE RESIS	STANCE						1	
Input Capacitance	C <sub>ISS</sub>			16013		pF		
Output Capacitance	C <sub>OSS</sub>	$V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}, V_{DS} = 20 \text{ V}$			6801			
Reverse Transfer Capacitance	C <sub>RSS</sub>				299			
Total Gate Charge	Q <sub>G(TOT)</sub>				126			
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 20 V; I <sub>D</sub> = 50 A			22.5		nC	
Gate-to-Source Charge	Q <sub>GS</sub>				39.9			
Gate-to-Drain Charge	$Q_{GD}$				38.4			
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 2	0 V; I <sub>D</sub> = 50 A		265		nC	
SWITCHING CHARACTERISTICS, V <sub>GS</sub> = 4.5	<b>V</b> (Note 4)						1	
Turn-On Delay Time	t <sub>d(ON)</sub>				89.4			
Rise Time	t <sub>r</sub>	Vcs = 4.5 V. Vn	e = 20 V.		111		- ns	
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$V_{GS} = 4.5 \text{ V}, V_{D}$ $I_{D} = 50 \text{ A}, R_{G}$	= 6 Ω		180			
Fall Time	t <sub>f</sub>				84.7			
DRAIN-SOURCE DIODE CHARACTERISTIC	S						I	
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.75	1.2		
		I <sub>S</sub> = 50 A	T <sub>J</sub> = 125°C		0.6			
Reverse Recovery Time	t <sub>RR</sub>		•		99.3			
Charge Time	t <sub>a</sub>	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 50 \text{ A}$			62.4		ns	
Discharge Time	t <sub>b</sub>				36.9			
Reverse Recovery Charge	Q <sub>RR</sub>				228		nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

4. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

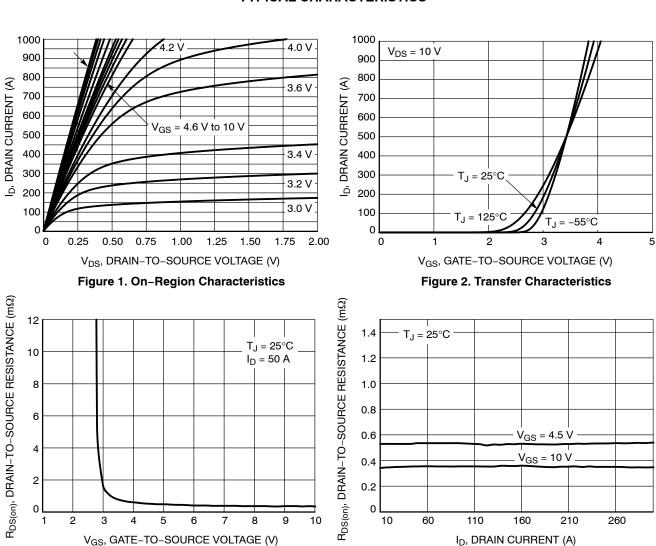


Figure 3. On-Resistance vs. Gate-to-Source Voltage

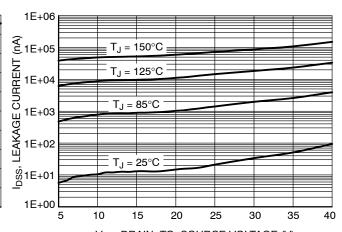


Figure 4. On-Resistance vs. Drain Current and

**Gate Voltage** 

0 -55 -15 25 65 105 145 T<sub>J</sub>, JUNCTION TEMPERATURE (°C) Figure 5. On-Resistance Variation with **Temperature** 

2.0

V<sub>GS</sub> = 10 V

 $I_D = 50 A$ 

V<sub>DS</sub>, DRAIN-TO-SOURCE VOLTAGE (V) Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

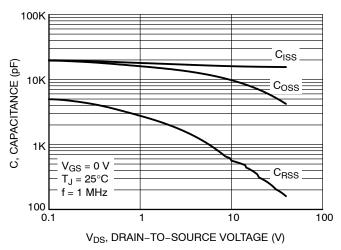


Figure 7. Capacitance Variation

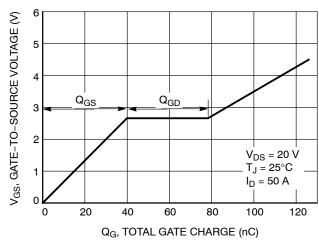


Figure 8. Gate-to-Source Voltage vs. Total Charge

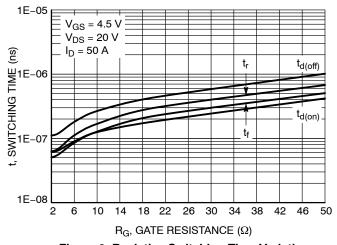


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

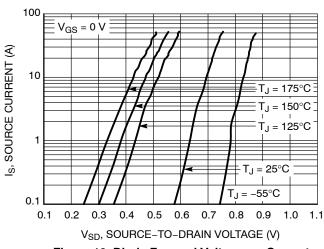


Figure 10. Diode Forward Voltage vs. Current

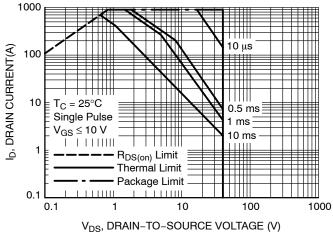


Figure 11. Maximum Rated Forward Biased Safe Operating Area

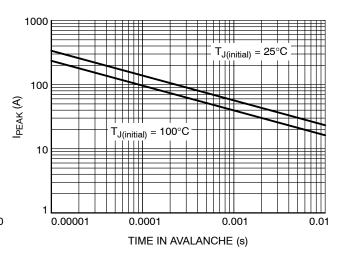


Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

#### **TYPICAL CHARACTERISTICS**

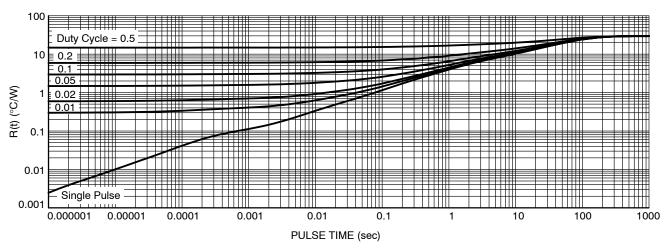


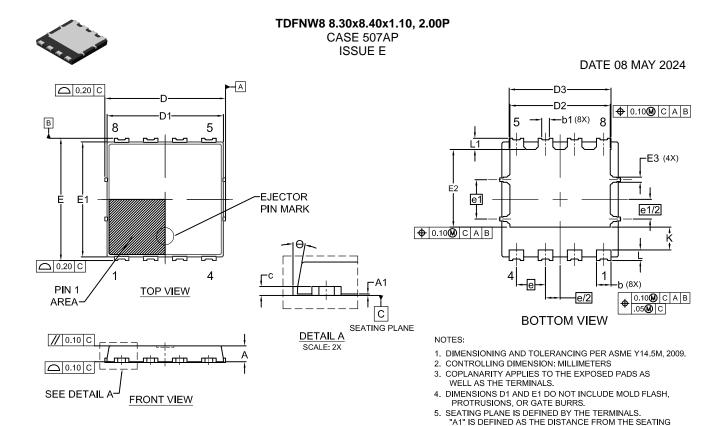
Figure 13. Thermal Characteristics

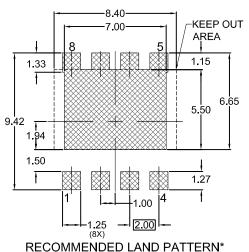
#### **DEVICE ORDERING INFORMATION**

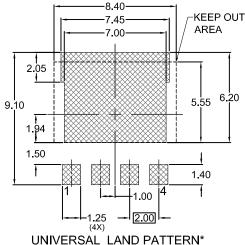
Device	Marking	Package	Shipping <sup>†</sup>
NVMTS0D6N04CLTXG	0D6N04CL	POWER 88 (Pb-Free)	3000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.









DIM	MILLIMETERS			
Divi	MIN.	MAX.		
Α	1.00	1.10	1.20	
A1	0.00	-	0.05	
b	0.90	1.00	1.10	
b1	0.35	0.45	0.55	
С	0.23	0.28	0.33	
D	8.20	8.30	8.40	
D1	7.90	8.00	8.10	
D2	6.80	6.90	7.00	
D3	6.90	7.00	7.10	
Е	8.30	8.40	8.50	
E1	7.80	7.90	8.00	
E2	5.24	5.34	5.44	
E3	0.25	0.35	0.45	
е		2.00 BS	С	
e/2		1.00 BS	С	
e1		2.70 BS	С	
e1/2	1.35 BSC			
K	1.50	1.57	1.70	
Г	0.64	0.74	0.84	
L1	0.67	0.77	0.87	
θ	0°		12°	

PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.

*FOR ADDITIONAL INFORMATION ON OUR PB-FREE	
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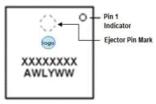
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CASE 507AP ISSUE E

**DATE 08 MAY 2024** 

## GENERIC MARKING DIAGRAM\*



XXXX = Specific Device Code
A = Assembly Location
WL = Wafer Lot Code
Y = Year Code
WW = Work Week Code

\*This information is generic. Please refer to device data sheet for actual part marking. Pb–Free indicator, "G" or microdot " •", may or may not be present. Some products may not follow the Generic Marking.

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